



RF Power Field Effect Transistor

N-Channel Enhancement-Mode Lateral MOSFET

Designed for pulsed wideband applications operating at frequencies between 3100 and 3500 MHz.

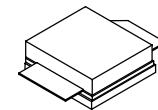
- Typical Pulsed Performance: $V_{DD} = 32$ Volts, $I_{DQ} = 50$ mA, $P_{out} = 15$ Watts Peak (3 Watts Avg.), Pulsed Signal, $f = 3500$ MHz, Pulse Width = 100 μ sec, Duty Cycle = 20%
 - Power Gain — 16 dB
 - Drain Efficiency — 41%
- Typical WiMAX Performance: $V_{DD} = 32$ Volts, $I_{DQ} = 150$ mA, $P_{out} = 1.8$ Watts Avg., $f = 3500$ MHz, 802.16d, 64 QAM $^{3/4}$, 4 Bursts, 10 MHz Channel Bandwidth, Input Signal PAR = 9.5 dB @ 0.01% Probability on CCDF
 - Power Gain — 18 dB
 - Drain Efficiency — 16%
 - RCE — -33 dB (EVM — 2.2% rms)
- Capable of Handling 10:1 VSWR, @ 32 Vdc, 3300 MHz, 15 Watts Peak Power
- Capable of Handling 3 dB Overdrive @ 32 Vdc

Features

- Characterized with Series Equivalent Large-Signal Impedance Parameters
- Internally Matched for Ease of Use
- Integrated ESD Protection
- Greater Negative Gate-Source Voltage Range for Improved Class C Operation
- RoHS Compliant
- In Tape and Reel. R3 Suffix = 250 Units, 32 mm Tape Width, 13 inch Reel.

MRF7S35015HSR3

**3100-3500 MHz, 15 W PEAK, 32 V
PULSED
LATERAL N-CHANNEL
RF POWER MOSFET**



**CASE 465J-02, STYLE 1
NI-400S-240**

Table 1. Maximum Ratings

| Rating | Symbol | Value | Unit |
|--------------------------------------|-----------|-------------|------|
| Drain-Source Voltage | V_{DSS} | -0.5, +65 | Vdc |
| Gate-Source Voltage | V_{GS} | -6.0, +10 | Vdc |
| Operating Voltage | V_{DD} | 32, +0 | Vdc |
| Storage Temperature Range | T_{stg} | -65 to +150 | °C |
| Case Operating Temperature | T_C | 150 | °C |
| Operating Junction Temperature (1,2) | T_J | 225 | °C |

Table 2. Thermal Characteristics

| Characteristic | Symbol | Value (2,3) | Unit |
|--|-----------------|--------------|------|
| Thermal Resistance, Junction to Case Case Temperature 80°C, 15 W Pulsed, 100 μ sec Pulse Width, 20% Duty Cycle Case Temperature 81°C, 15 W Pulsed, 500 μ sec Pulse Width, 10% Duty Cycle | $R_{\theta JC}$ | 0.60 0.73 | °C/W |

- Continuous use at maximum temperature will affect MTTF.
- MTTF calculator available at <http://www.freescale.com/rf>. Select Software & Tools/Development Tools/Calculators to access MTTF calculators by product.
- Refer to AN1955, *Thermal Measurement Methodology of RF Power Amplifiers*. Go to <http://www.freescale.com/rf>. Select Documentation/Application Notes - AN1955.

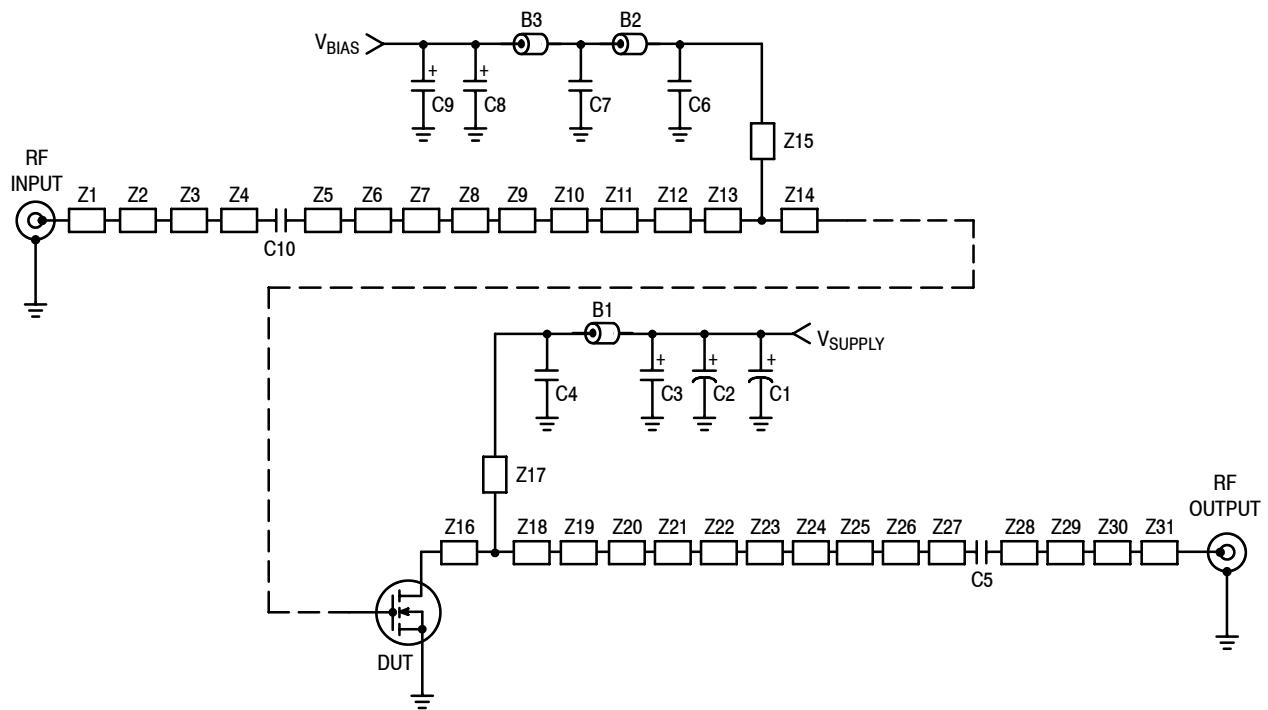
Table 3. ESD Protection Characteristics

| Test Methodology | Class |
|---------------------------------------|--------------|
| Human Body Model (per JESD22-A114) | 1B (Minimum) |
| Machine Model (per EIA/JESD22-A115) | A (Minimum) |
| Charge Device Model (per JESD22-C101) | IV (Minimum) |

Table 4. Electrical Characteristics ($T_C = 25^\circ\text{C}$ unless otherwise noted)

| Characteristic | Symbol | Min | Typ | Max | Unit |
|---|---------------------|--------------------------------|------|-----|-----------------|
| Off Characteristics | | | | | |
| Gate-Source Leakage Current ($V_{GS} = 5 \text{ Vdc}$, $V_{DS} = 0 \text{ Vdc}$) | I_{GSS} | — | — | 1 | μAdc |
| Zero Gate Voltage Drain Leakage Current ($V_{DS} = 32 \text{ Vdc}$, $V_{GS} = 0 \text{ Vdc}$) | I_{DSS} | — | — | 2 | μAdc |
| Zero Gate Voltage Drain Leakage Current ($V_{DS} = 65 \text{ Vdc}$, $V_{GS} = 0 \text{ Vdc}$) | I_{DSS} | — | — | 10 | μAdc |
| On Characteristics | | | | | |
| Gate Threshold Voltage ($V_{DS} = 10 \text{ Vdc}$, $I_D = 33.5 \mu\text{Adc}$) | $V_{GS(\text{th})}$ | 1.2 | 2 | 2.7 | Vdc |
| Gate Quiescent Voltage ($V_{DD} = 32 \text{ Vdc}$, $I_D = 50 \text{ mA}$, Measured in Functional Test) | $V_{GS(Q)}$ | 1.8 | 2.5 | 3.3 | Vdc |
| Drain-Source On-Voltage ($V_{GS} = 10 \text{ Vdc}$, $I_D = 300 \text{ mA}$) | $V_{DS(\text{on})}$ | 0.1 | 1.7 | 0.3 | Vdc |
| Dynamic Characteristics ⁽¹⁾ | | | | | |
| Reverse Transfer Capacitance ($V_{DS} = 32 \text{ Vdc} \pm 30 \text{ mV(rms)ac}$ @ 1 MHz, $V_{GS} = 0 \text{ Vdc}$) | C_{rss} | — | 0.12 | — | pF |
| Output Capacitance ($V_{DS} = 32 \text{ Vdc} \pm 30 \text{ mV(rms)ac}$ @ 1 MHz, $V_{GS} = 0 \text{ Vdc}$) | C_{oss} | — | 92 | — | pF |
| Input Capacitance ($V_{DS} = 32 \text{ Vdc}$, $V_{GS} = 0 \text{ Vdc} \pm 30 \text{ mV(rms)ac}$ @ 1 MHz) | C_{iss} | — | 46 | — | pF |
| Functional Tests (In Freescale Test Fixture, 50 ohm system) $V_{DD} = 32 \text{ Vdc}$, $I_{DQ} = 50 \text{ mA}$, $P_{out} = 15 \text{ W Peak}$ (3 W Avg.), $f = 3100 \text{ MHz}$ and $f = 3500 \text{ MHz}$, Pulsed, 100 μsec Pulse Width, 20% Duty Cycle, 25 ns Input Rise Time | | | | | |
| Power Gain | G_{ps} | 13 | 16 | 19 | dB |
| Drain Efficiency | η_D | 38 | 41 | — | % |
| Input Return Loss | IRL | — | -12 | -7 | dB |
| Pulsed RF Performance (In Freescale Application Test Fixture, 50 ohm system) $V_{DD} = 32 \text{ Vdc}$, $I_{DQ} = 50 \text{ mA}$, $P_{out} = 15 \text{ W Peak}$ (3 W Avg.), $f = 3100 \text{ MHz}$ and $f = 3500 \text{ MHz}$, Pulsed, 100 μsec Pulse Width, 20% Duty Cycle, 25 ns Input Rise Time | | | | | |
| Output Pulse Droop (500 μsec Pulse Width, 10% Duty Cycle) | DRP_{out} | — | 0.2 | — | dB |
| Load Mismatch Tolerance (VSWR = 10:1 at all Phase Angles) | VSWR-T | No Degradation in Output Power | | | |

1. Part internally matched both on input and output.



| | | | |
|------|----------------------------|-----|--|
| Z1 | 0.375" x 0.071" Microstrip | Z18 | 0.078" x 0.454" Microstrip |
| Z2 | 0.126" x 0.524" Microstrip | Z19 | 0.055" x 0.244" Microstrip |
| Z3 | 0.079" x 0.016" Microstrip | Z20 | 0.630" x 0.073" Microstrip |
| Z4 | 0.153" x 0.071" Microstrip | Z21 | 0.218" x 0.038" Microstrip |
| Z5 | 0.076" x 0.520" Microstrip | Z22 | 0.060" x 0.552" Microstrip |
| Z6 | 0.037" x 0.252" Microstrip | Z23 | 0.079" x 0.038" Microstrip |
| Z7 | 0.322" x 0.073" Microstrip | Z24 | 0.062" x 0.526" Microstrip |
| Z8 | 0.123" x 0.440" Microstrip | Z25 | 0.032" x 0.070" Microstrip |
| Z9 | 0.048" x 0.073" Microstrip | Z26 | 0.110" x 0.526" Microstrip |
| Z10 | 0.081" x 0.184" Microstrip | Z27 | 0.053" x 0.072" Microstrip |
| Z11 | 0.030" x 0.262" Microstrip | Z28 | 0.028" x 0.070" Microstrip |
| Z12 | 0.525" x 0.336" Microstrip | Z29 | 0.098" x 0.148" Microstrip |
| Z13 | 0.182" x 0.466" Microstrip | Z30 | 0.062" x 0.526" Microstrip |
| Z14 | 0.077" x 0.466" Microstrip | Z31 | 0.529" x 0.070" Microstrip |
| Z15* | 0.603" x 0.048" Microstrip | PCB | Arlon CuClad 250GX-0300-55-22, 0.030", $\epsilon_r = 2.55$ |
| Z16 | 0.063" x 0.618" Microstrip | | |
| Z17* | 0.534" x 0.040" Microstrip | | * Line length includes microstrip bends |

Figure 1. MRF7S35015HSR3 Test Circuit Schematic

Table 5. MRF7S35015HSR3 Test Circuit Component Designations and Values

| Part | Description | Part Number | Manufacturer |
|-------------|--|-------------------|--------------|
| B1* | Long Ferrite Bead | 2743021447 | Fair-Rite |
| B2, B3 | Short Ferrite Beads | 2743019447 | Fair-Rite |
| C1 | 470 μ F, 63 V Electrolytic Capacitor | 477KXM063M | Illinois Cap |
| C2 | 47 μ F, 50 V Electrolytic Capacitor | 476KXM050M | Illinois Cap |
| C3, C9 | 22 μ F, 35 V Tantalum Capacitors | T491X226K035AT | Kemet |
| C4, C5, C10 | 2.7 pF Chip Capacitors | ATC100B2R7BT500XT | ATC |
| C6 | 0.8 pF Chip Capacitor | ATC100B0R8BT500XT | ATC |
| C7 | 0.1 μ F Chip Capacitor | CDR33BX104AKYS | AVX |
| C8 | 22 μ F, 25 V Tantalum Capacitor | T491D226K025AT | Kemet |

*B1 is removed for WiMAX circuit performance.

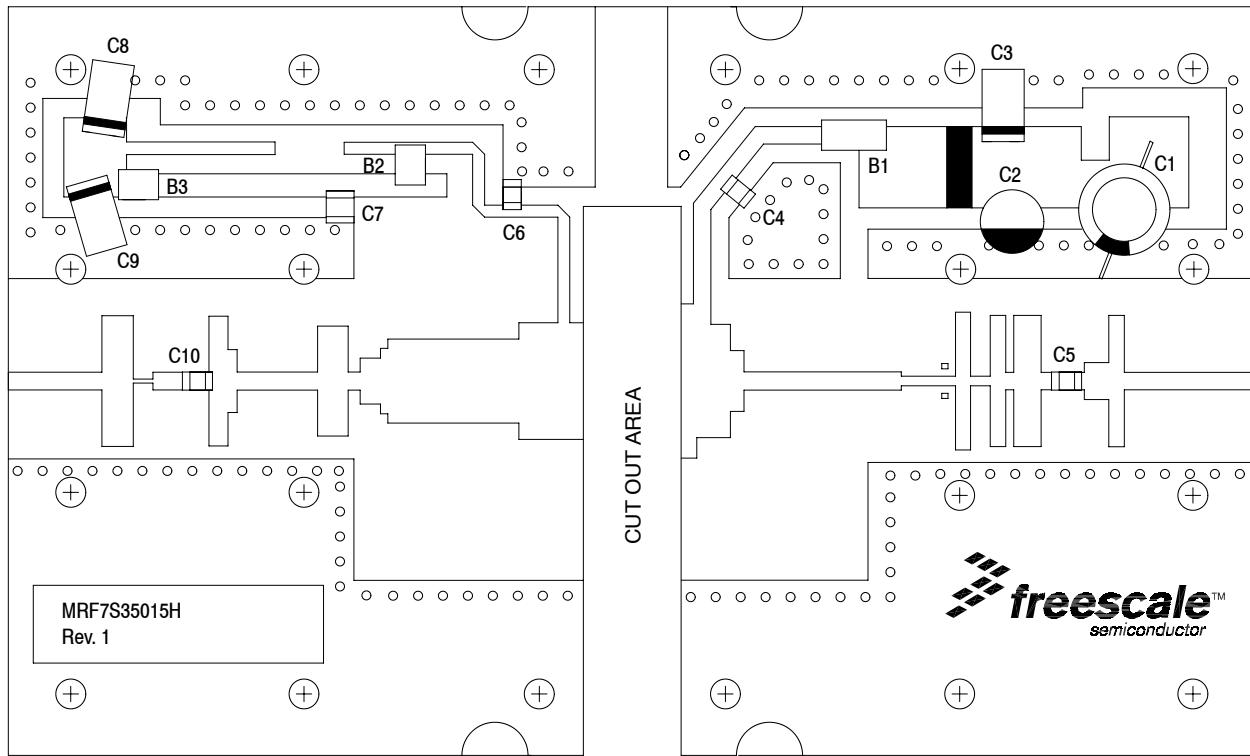


Figure 2. MRF7S35015HSR3 Test Circuit Component Layout

TYPICAL CHARACTERISTICS

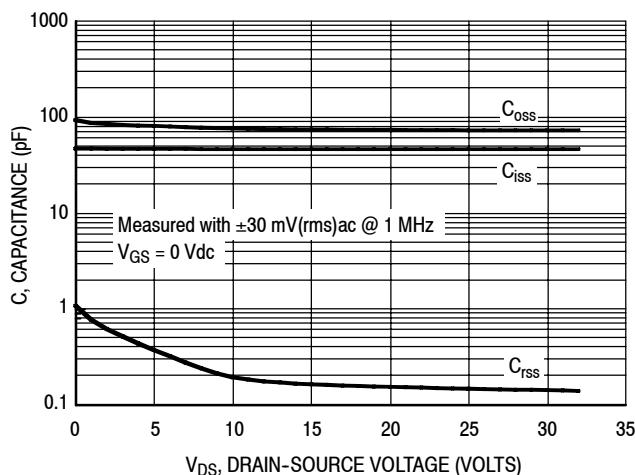


Figure 3. Capacitance versus Drain-Source Voltage

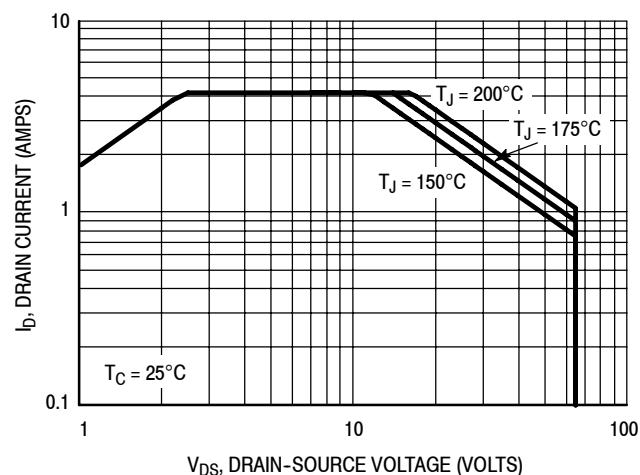


Figure 4. DC Safe Operating Area

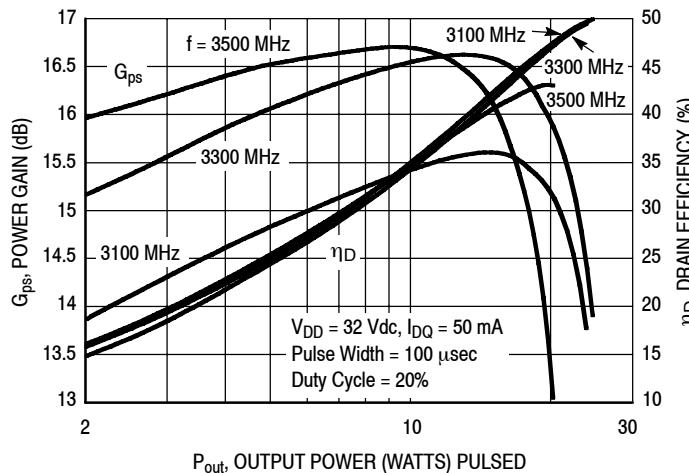


Figure 5. Pulsed Power Gain and Drain Efficiency versus Output Power

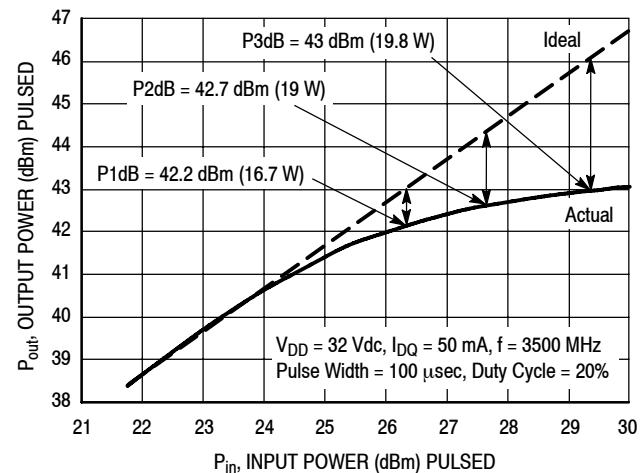


Figure 6. Pulsed Output Power versus Input Power

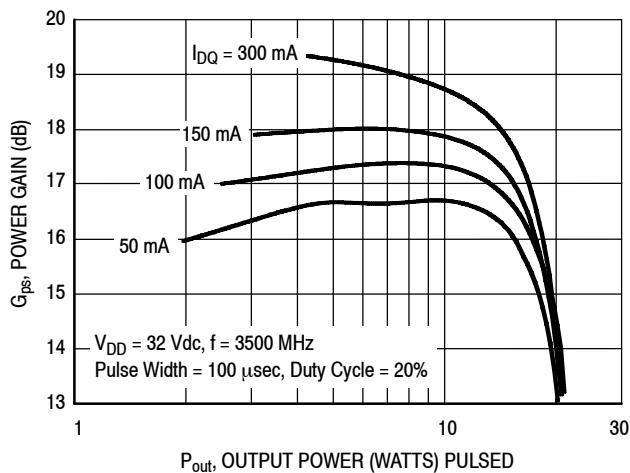


Figure 7. Pulsed Power Gain versus Output Power

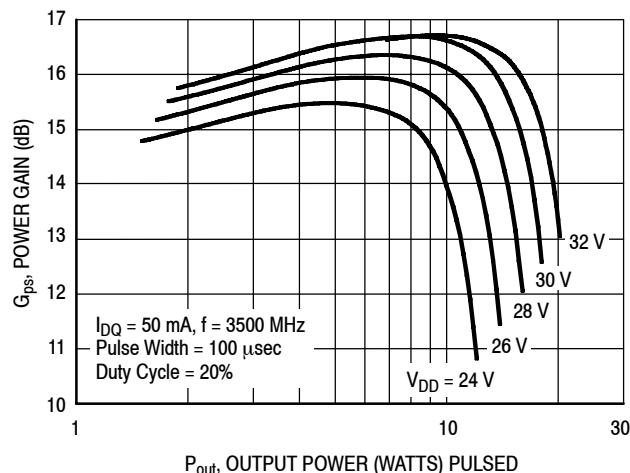


Figure 8. Pulsed Power Gain versus Output Power

TYPICAL CHARACTERISTICS

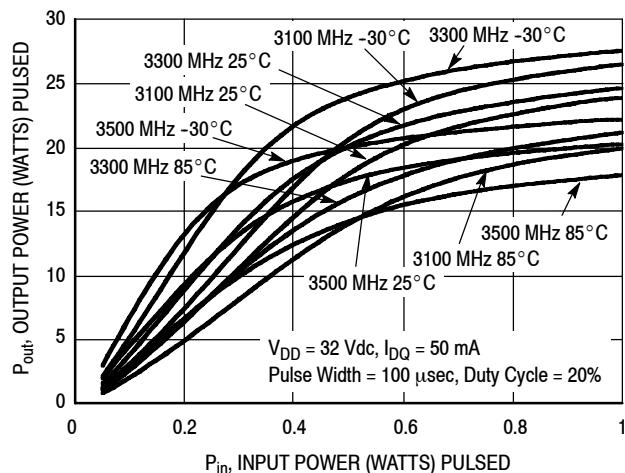


Figure 9. Pulsed Output Power versus Input Power

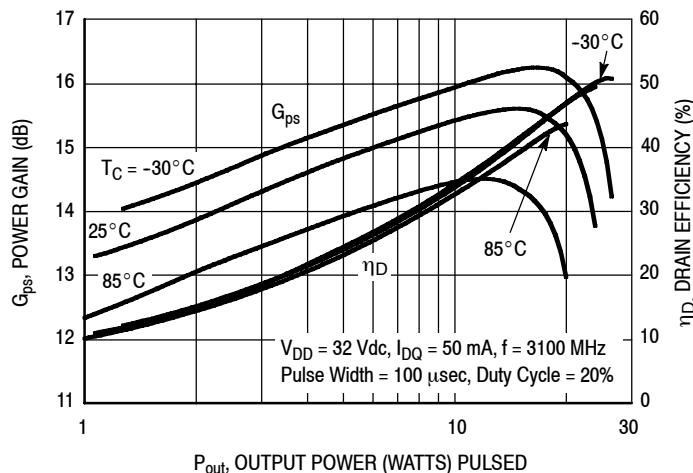


Figure 10. Pulsed Power Gain and Drain Efficiency versus Output Power — 3100 MHz

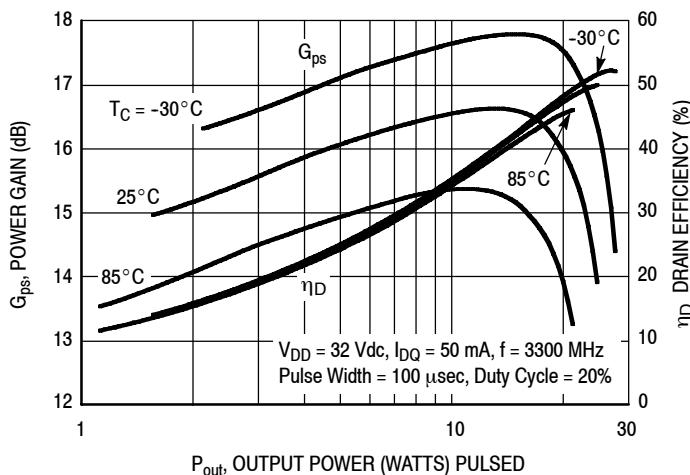


Figure 11. Pulsed Power Gain and Drain Efficiency versus Output Power — 3300 MHz

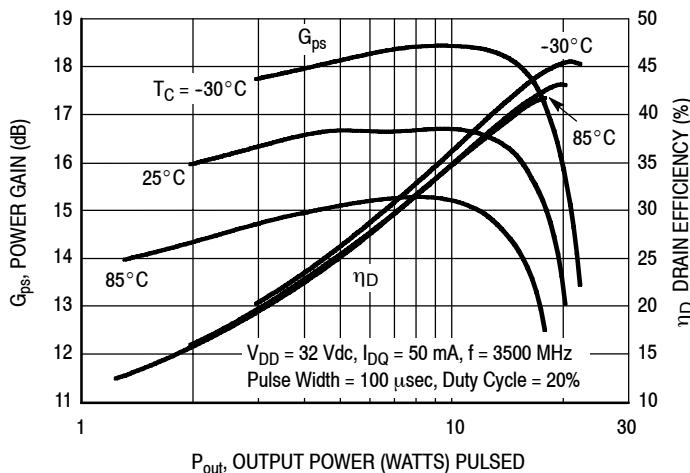


Figure 12. Pulsed Power Gain and Drain Efficiency versus Output Power — 3500 MHz

TYPICAL CHARACTERISTICS

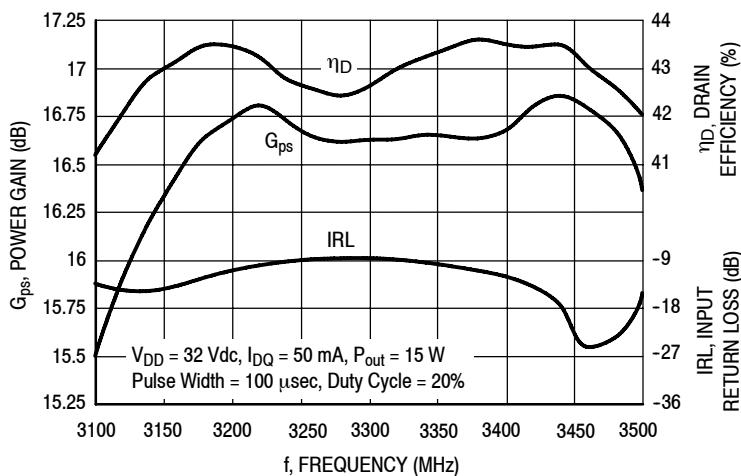


Figure 13. Pulsed Power Gain, Drain Efficiency and IRL versus Frequency

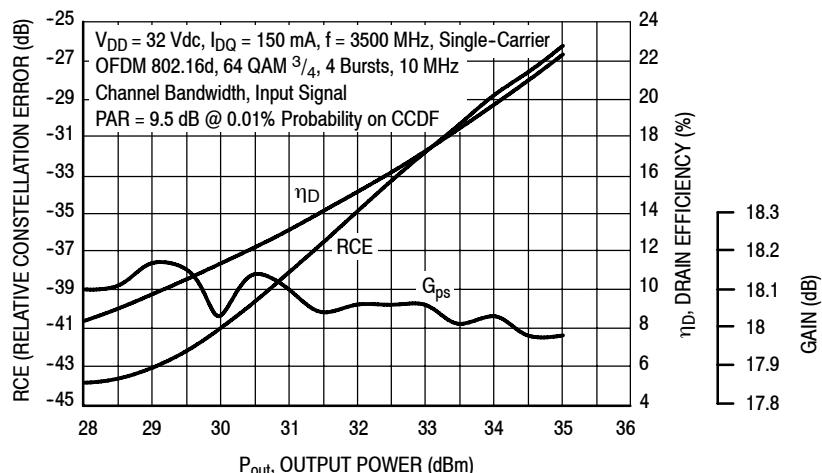
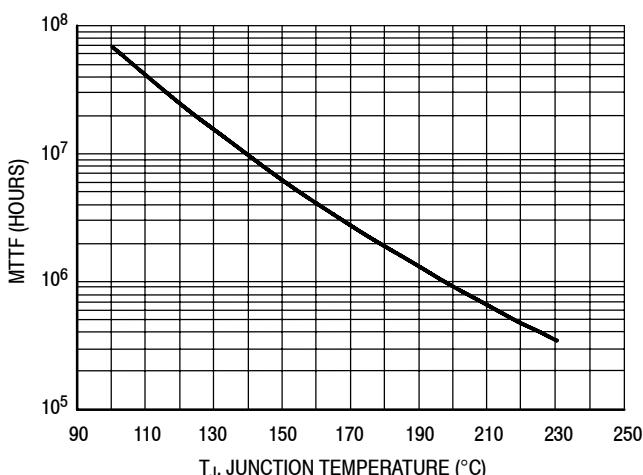


Figure 14. Single-Channel OFDM Relative Constellation Error, Drain Efficiency and Gain versus Output Power

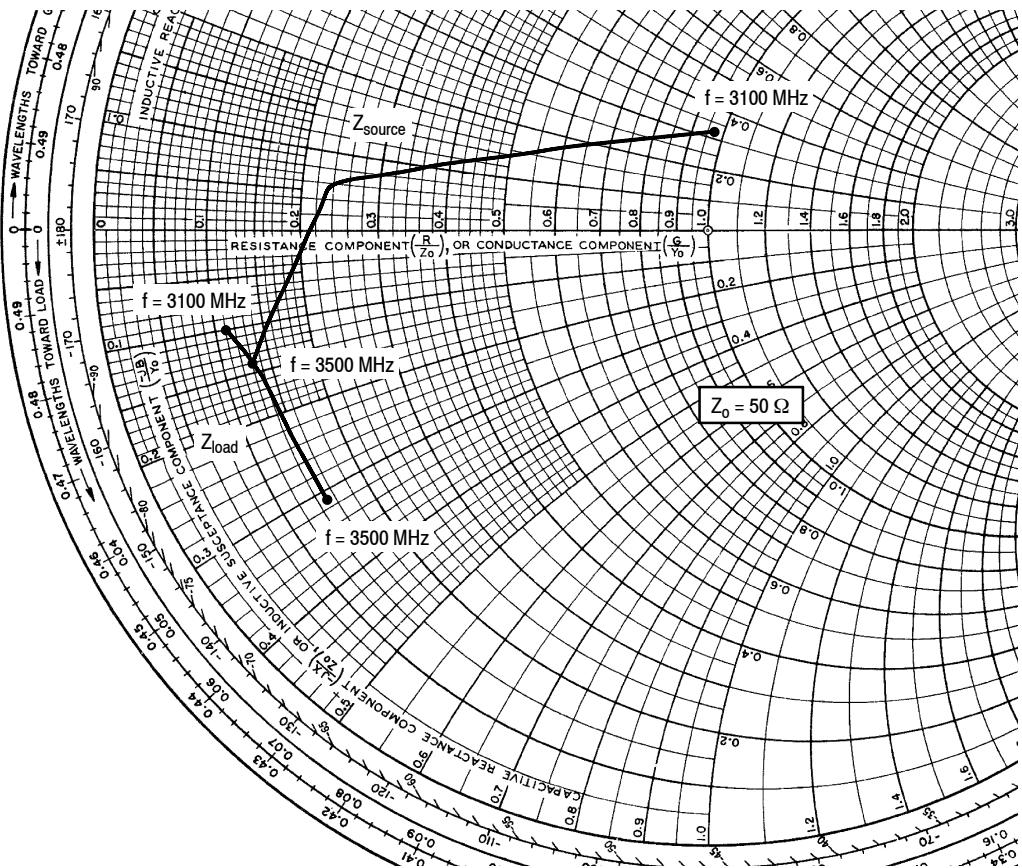


This above graph displays calculated MTTF in hours when the device is operated at $V_{DD} = 32 \text{ Vdc}$, $P_{out} = 15 \text{ W Peak}$, Pulse Width = 100 μsec , Duty Cycle = 20%, and $\eta_D = 41\%$.

MTTF calculator available at <http://www.freescale.com/rf>. Select Software & Tools/Development Tools/Calculators to access MTTF calculators by product.

Figure 15. MTTF versus Junction Temperature

MRF7S35015HSR3



$V_{DD} = 32$ Vdc, $I_{DQ} = 50$ mA, $P_{out} = 15$ W Peak

| f MHz | Z_{source} Ω | Z_{load} Ω |
|----------|--------------------------|------------------------|
| 3100 | $48.6 + j16.1$ | $5.6 - j5.2$ |
| 3300 | $11.8 + j3.15$ | $6.36 - j6.83$ |
| 3500 | $6.43 - j6.79$ | $7.41 - j15.5$ |

Z_{source} = Test circuit impedance as measured from gate to ground.

Z_{load} = Test circuit impedance as measured from drain to ground.

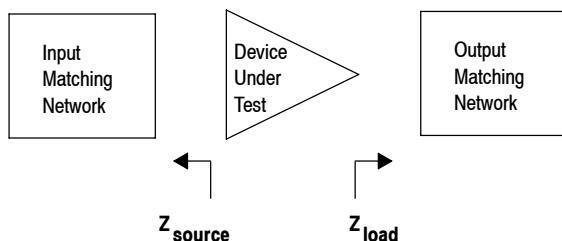
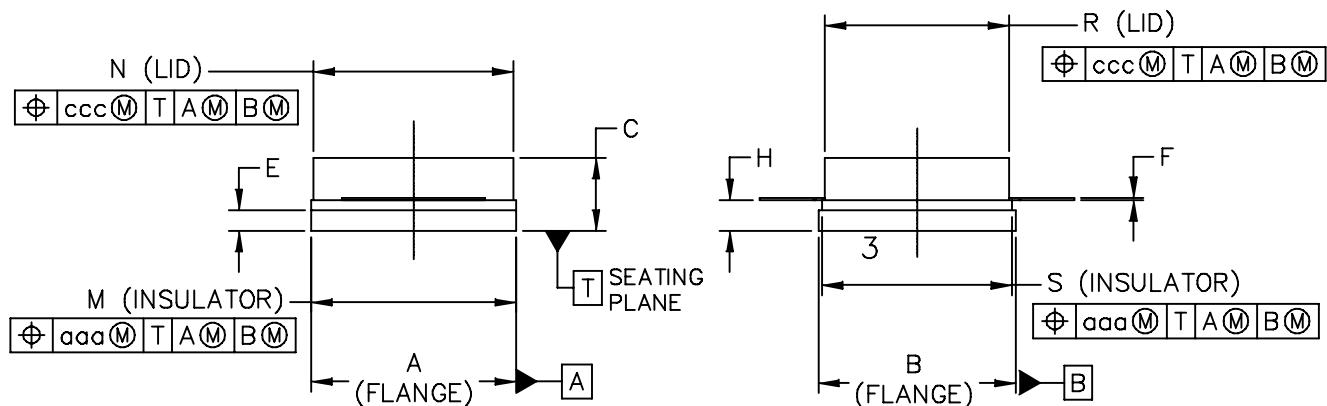
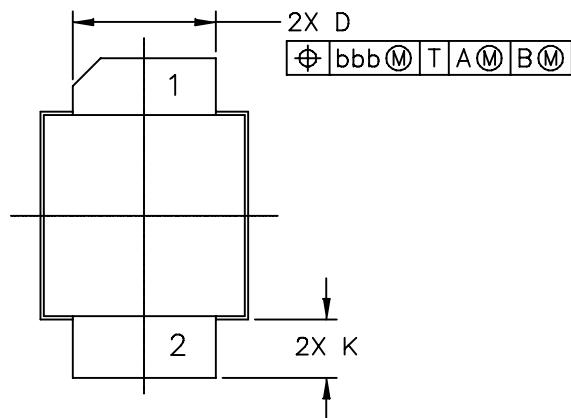


Figure 16. Series Equivalent Source and Load Impedance

PACKAGE DIMENSIONS



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| | | STANDARD: NON-JEDEC |

MRF7S35015HSR3

NOTES:

1. CONTROLLING DIMENSION: INCH
2. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M-1994.
3. DIMENSION H IS MEASURED .030 (0.762) AWAY FROM PACKAGE BODY

STYLE 1:

PIN 1 - DRAIN
2 - GATE
3 - SOURCE

STYLE 2:

PIN 1 - GATE
2 - DRAIN
3 - SOURCE

| DIM | INCH | | MILLIMETER | | DIM | INCH | | MILLIMETER | |
|-----|-------|-------|------------|-------|-----|------|-----|------------|-----|
| | MIN | MAX | MIN | MAX | | MIN | MAX | MIN | MAX |
| A | .395 | .405 | 10.03 | 10.29 | aaa | .005 | | 0.127 | |
| B | .380 | .390 | 9.65 | 9.91 | bbb | .010 | | 0.254 | |
| C | .125 | .163 | 3.18 | 4.14 | ccc | .015 | | 0.381 | |
| D | .275 | .285 | 6.98 | 7.24 | | | | | |
| E | .035 | .045 | 0.89 | 1.14 | | | | | |
| F | .004 | .006 | 0.10 | 0.15 | | | | | |
| H | .057 | .067 | 1.45 | 1.70 | | | | | |
| K | .0995 | .1295 | 2.53 | 3.29 | | | | | |
| M | .395 | .405 | 10.03 | 10.29 | | | | | |
| N | .385 | .395 | 9.78 | 10.03 | | | | | |
| R | .355 | .365 | 9.02 | 9.27 | | | | | |
| S | .365 | .375 | 9.27 | 9.53 | | | | | |

| | | |
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PRODUCT DOCUMENTATION

Refer to the following documents to aid your design process.

Application Notes

- AN1955: Thermal Measurement Methodology of RF Power Amplifiers

Engineering Bulletins

- EB212: Using Data Sheet Impedances for RF LDMOS Devices

REVISION HISTORY

The following table summarizes revisions to this document.

| Revision | Date | Description |
|----------|-----------|--|
| 0 | June 2008 | <ul style="list-style-type: none">Initial Release of Data Sheet |
| 1 | Aug. 2008 | <ul style="list-style-type: none">Added p. 1 of Case 465J-02 Mechanical Outline drawing, p. 9 |
| 2 | Apr. 2011 | <ul style="list-style-type: none">Fig. 1, Test Circuit Schematic, Z-list, changed Z7 from 0.084" x 0.73" Microstrip to 0.322" x 0.073" Microstrip and moved footnote reference from Z2 and Z3 to Z15 and Z17, p. 3 |

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